

Search Notes**Application/Control No.**

10/700,119

Examiner

Ren L. Yan

Applicant(s)/Patent under Reexamination

BECKER ET AL.

Art Unit

2854

SEARCHED

Class	Subclass	Date	Examiner
101	229 230	2/16/05	R.yan
	408		
	409		
271	275		
	276		
	277		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

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